
Integrirana vezja - Meritve elektromagnetnega sevanja, od 150 kHz do 1 GHz - 4.
del: Meritve prevajanega sevanja - Metoda neposrednega sklopa 1 ohm/150 ohmov
- Popravek AC (IEC 61967-4:2002/COR1:2017)

Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method (IEC 61967-4:2002/COR1:2017)

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Integrierte Schaltungen - Messung von elektromagnetischen Aussendungen im Frequenzbereich von 150 kHz bis 1 GHz - Teil 4: Messung der leitungsgeführten Aussendungen - Messung mit direkter 1 Ohm/150 Ohm-Kopplung (IEC 61967-4:2002/COR1:2017)

[SIST EN 61967-4:2005/AC:2017](https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90b-2c49a15430a8/sist-en-61967-4-2005-ac-2017)

<https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90b-2c49a15430a8/sist-en-61967-4-2005-ac-2017>

Circuits intégrés - Mesure des émissions électromagnétiques, 150 kHz à 1 GHz - Partie 4: Mesure des émissions conduites - Méthode par couplage direct 1 ohm/150 ohm (IEC 61967-4:2002/COR1:2017)

Ta slovenski standard je istoveten z: EN 61967-4:2002/AC:2017-07

ICS:

31.200	Integrirana vezja, mikroelektronika	Integrated circuits. Microelectronics
33.100.10	Emisija	Emission

SIST EN 61967-4:2005/AC:2017 **en**

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[SIST EN 61967-4:2005/AC:2017](https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90b3-2c49a15430a8/sist-en-61967-4-2005-ac-2017)

<https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90b3-2c49a15430a8/sist-en-61967-4-2005-ac-2017>

EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 61967-4:2002/AC:2017-07

July 2017

ICS 31.200

English Version

**Integrated circuits - Measurement of electromagnetic emissions,
150 kHz to 1 GHz - Part 4: Measurement of conducted
emissions - 1 ohm/150 ohm direct coupling method
(IEC 61967-4:2002/COR1:2017)**

Circuits intégrés - Mesure des émissions
électromagnétiques, 150 kHz à 1 GHz - Partie 4: Mesure
des émissions conduites - Méthode par couplage direct 1
ohm/150 ohm
(IEC 61967-4:2002/COR1:2017)

Integrierte Schaltungen - Messung von
elektromagnetischen Aussendungen im Frequenzbereich
von 150 kHz bis 1 GHz - Teil 4: Messung der
leitungsgeführten Aussendungen - Messung mit direkter 1
Ohm/150 Ohm-Kopplung
(IEC 61967-4:2002/COR1:2017)

This corrigendum becomes effective on 21 July 2017 for incorporation in the English language version of the EN.

**ITeh STANDARD PREVIEW
(standards.iteh.ai)**

[SIST EN 61967-4:2005/AC:2017](https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90B-2c49a15430a8/sist-en-61967-4-2005-ac-2017)

<https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90B-2c49a15430a8/sist-en-61967-4-2005-ac-2017>



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Endorsement notice

The text of the corrigendum IEC 61967-4:2002/COR1:2017 was approved by CENELEC as EN 61967-4:2002/AC:2017-07 without any modification.

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[SIST EN 61967-4:2005/AC:2017](https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90B-2c49a15430a8/sist-en-61967-4-2005-ac-2017)

<https://standards.iteh.ai/catalog/standards/sist/791cba7e-a96f-4683-90B-2c49a15430a8/sist-en-61967-4-2005-ac-2017>

INTERNATIONAL ELECTROTECHNICAL COMMISSION
COMMISSION ÉLECTROTECHNIQUE INTERNATIONALEIEC 61967-4
Edition 1.0 2002-04Integrated circuits – Measurement of
electromagnetic emissions, 150 kHz to 1 GHzPart 4:
Measurement of conducted emissions –
1 Ω /150 Ω direct coupling methodIEC 61967-4
Édition 1.0 2002-04Circuits intégrés – Mesure des émissions
électromagnétiques, 150 kHz à 1 GHzPartie 4:
Mesure des émissions conduites –
Méthode par couplage direct 1 Ω /150 Ω

CORRIGENDUM 1

Corrections to the French version appear after the English text.

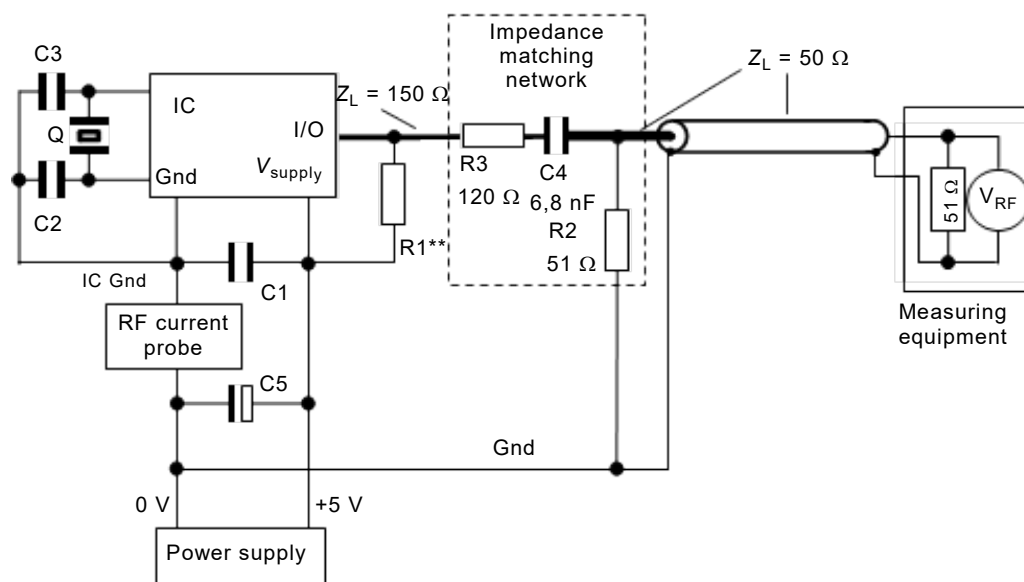
Les corrections à la version française sont données après le texte anglais.

ITC STANDARD PREVIEW
(standards.iteh.ai)

SIST EN 61967-4:2005/AC:2017

7.1 General test configuration

Replace the existing Figure 5 by the following new Figure 5:



** pull up / pull down may be required depending on application

IEC

Figure 5 – General test configuration